

FORM PTO-1449 (REV. 7-80)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. H&A-127	SERIAL NO.		
LIST OF DOCUMENTS CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				APPLICANT S. OGAWA et al			
				FILING DATE March 1, 2004		GROUP	
U.S. PATENT DOCUMENTS							
* EXAMINER INITIAL		DOCUMENT	DATE	NAME	CLASS	SUBCLASS	FILING DATE <i>(If Appropriate)</i>
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
<div style="font-size: 2em; font-family: cursive;">F/T</div>	AL	2001-196661	7/19/01	Japan	/	/	<input type="checkbox"/> <input type="checkbox"/>
	AM	11-73906	3/16/99	Japan	/	/	<input type="checkbox"/> <input type="checkbox"/>
	AN	5-250735	9/28/93	Japan	/	/	<input checked="" type="checkbox"/> <input type="checkbox"/>
	AO	2000-215627	8/4/00	Japan	/	/	<input type="checkbox"/> <input type="checkbox"/>
	AP						<input type="checkbox"/> <input type="checkbox"/>
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, etc.)</i>							
<div style="font-size: 2em; font-family: cursive;">F/T</div>	AR	Mattsonet et al, Phys. Rev. Lett., 71, 185 1993.					
<div style="font-size: 2em; font-family: cursive;">F/T</div>	AS	Chun-Yoel Youi et al, J. App. Phys. 87, 5215, 2000.					
<div style="font-size: 2em; font-family: cursive;">F/T</div>	AT	Stefan Grafstrom, Appl. Phys. Rev., 91, 1717, 2002.					
EXAMINER <div style="font-size: 1.5em; font-family: cursive;">Fred Tzeny</div>				DATE CONSIDERED <div style="font-size: 1.5em; font-family: cursive;">12/11/05</div>			
<small>* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							